

## TC74HC595AP, TC74HC595AF, TC74HC595AFN

### 8-Bit Shift Register/Latch (3-state)

The TC74HC595A is a high speed 8-BIT SHIFT REGISTER/LATCH fabricated with silicon gate C2MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

The TC74HC595A contains an 8-bit static shift register which feeds an 8-bit storage register.

Shift operation is accomplished on the positive going transition of the SCK input. The output register is loaded with the contents of the shift register on the positive going transition of the RCK input. Since RCK and SCK signal are independent, parallel outputs can be held stable during the shift operation.

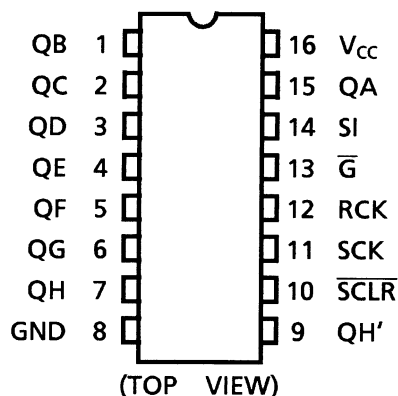
And, since the parallel outputs are 3-state, it can be directly connected to 8-bit bus. This register can be used in serial-to-parallel conversion, data receivers, etc.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

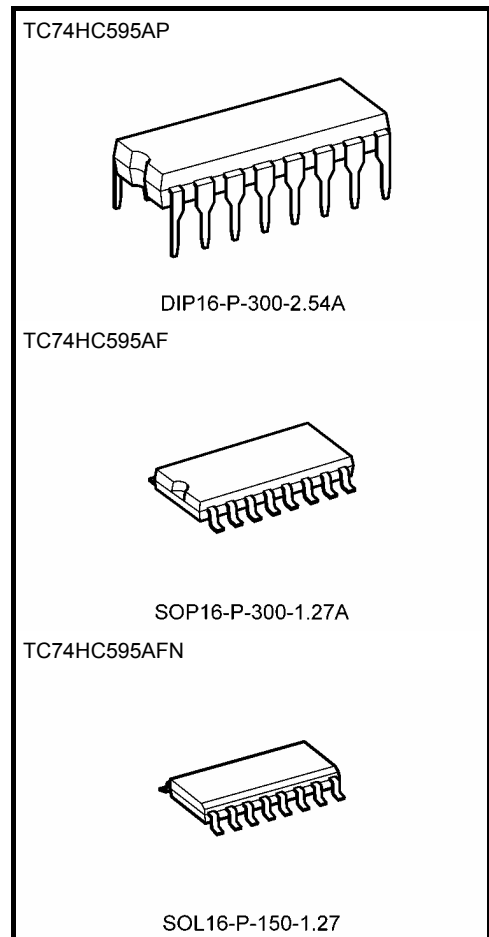
### Features

- High speed:  $f_{max} = 55 \text{ MHz (typ.)}$  at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 4 \mu\text{A (max)}$  at  $T_a = 25^\circ\text{C}$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC} \text{ (min)}$
- Output drive capability: 15 LSTTL loads for QA to QH  
10 LSTTL loads for QH'
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 6 \text{ mA (min)}$   
For QA to QH  
 $|I_{OH}| = I_{OL} = 4 \text{ mA (min)}$   
For QH'
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} \text{ (opr)} = 2 \text{ to } 6 \text{ V}$
- Pin and function compatible with 74LS595

### Pin Assignment



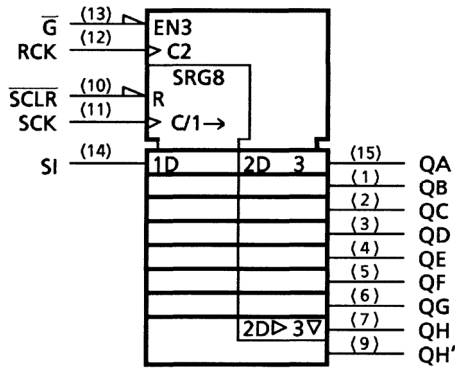
Note: xxxFN (JEDEC SOP) is not available in Japan.



### Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

## IEC Logic Symbol

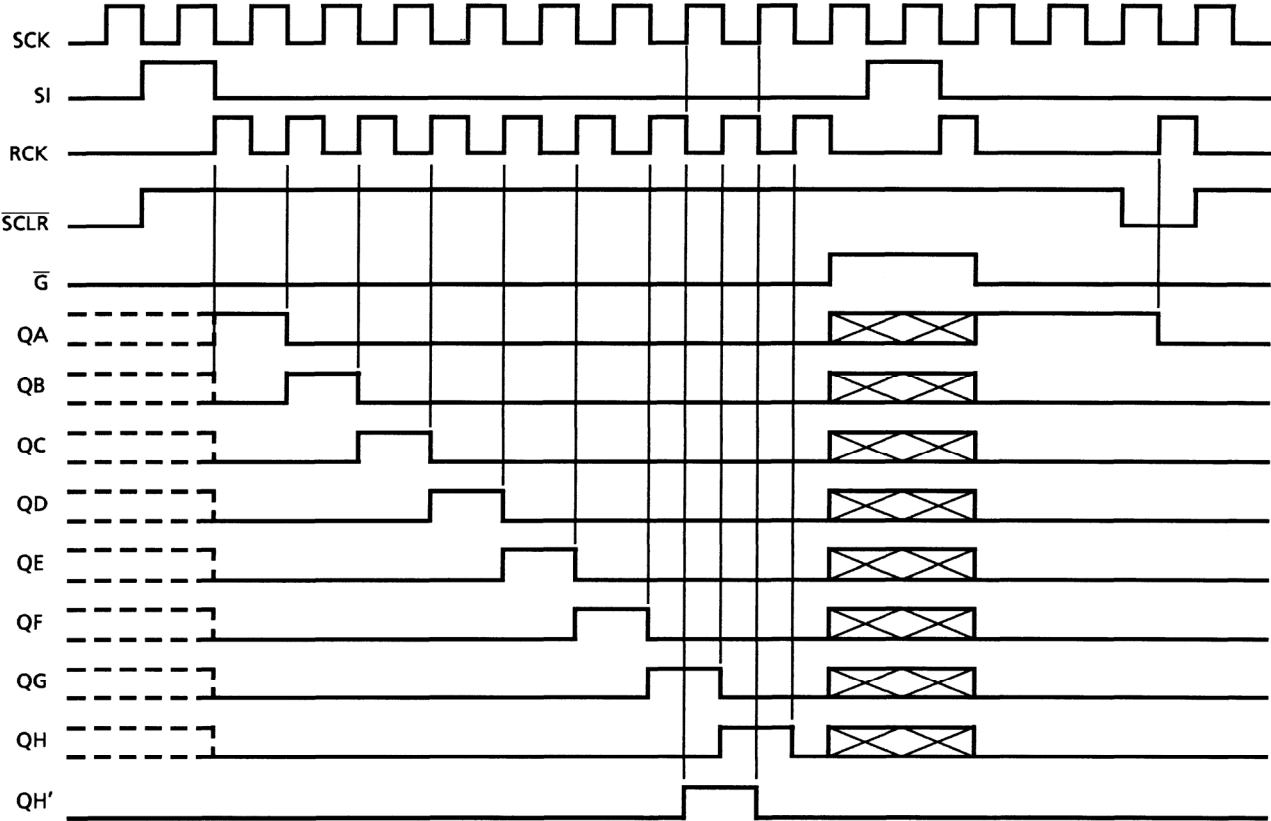


## Truth Table

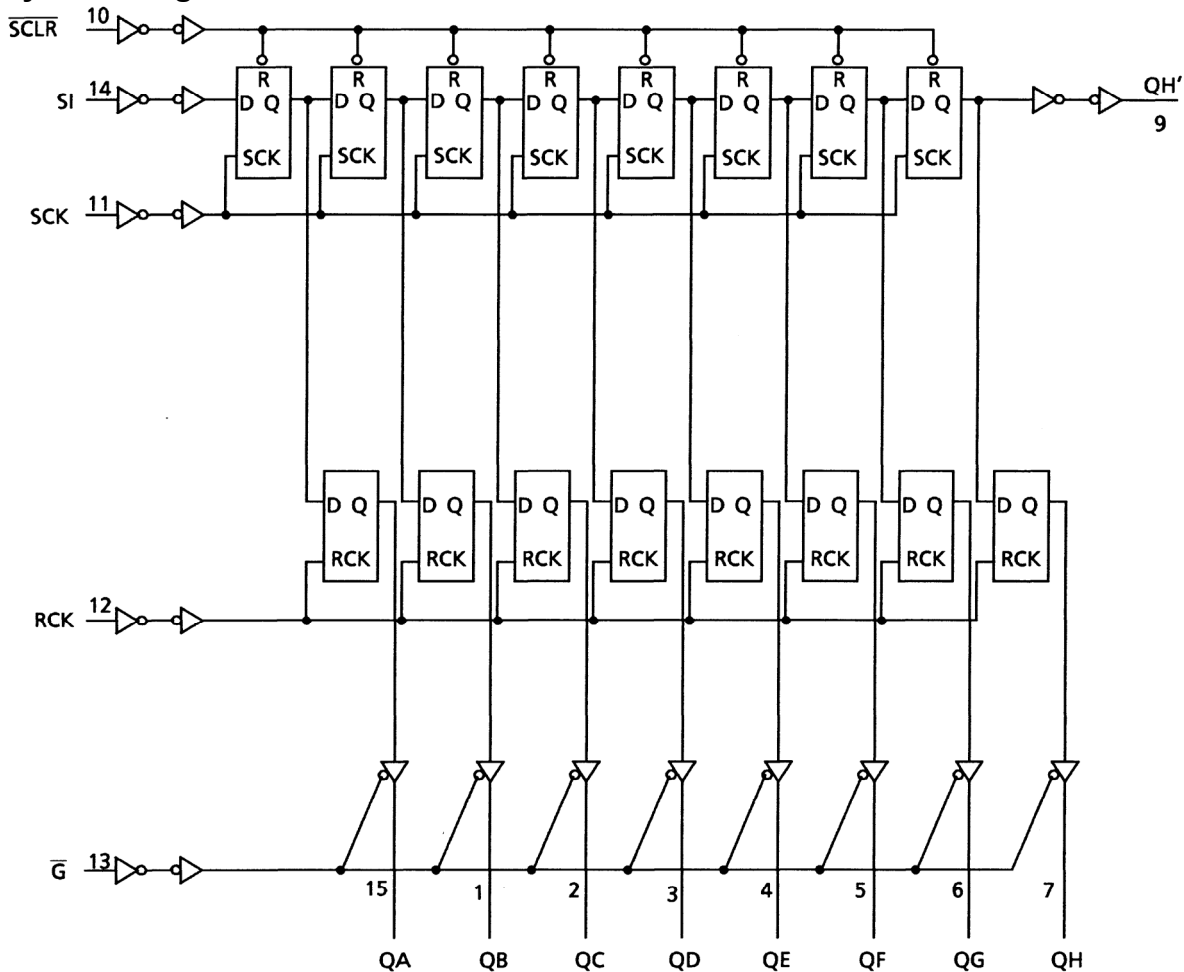
Inputs					Function
SI	SCK	SCLR	RCK	G-bar	
X	X	X	X	H	QA thru QH outputs disable
X	X	X	X	L	QA thru QH outputs enable
X	X	L	X	X	Shift register is cleared.
L		H	X	X	First stage of S.R. becomes "L". Other stages store the data of previous stage, respectively.
H		H	X	X	First stage of S.R. becomes "H". Other stages store the data of previous stage, respectively.
X		H	X	X	State of S.R. is not changed.
X	X	X		X	S.R. data is stored into storage register.
X	X	X		X	Storage register stage is not changed.

X: Don't care

Timing Chart



## System Diagram



## Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5 to 7	V
DC input voltage	$V_{IN}$	-0.5 to $V_{CC} + 0.5$	V
DC output voltage	$V_{OUT}$	-0.5 to $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	$\pm 20$	mA
Output diode current	$I_{OK}$	$\pm 20$	mA
DC output current (QH') (QA to QH)	$I_{OUT}$	$\pm 25$ $\pm 35$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 75$	mA
Power dissipation	$P_D$	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	$T_{stg}$	-65 to 150	$^{\circ}C$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Note 2: 500 mW in the range of  $T_a = -40$  to  $65^{\circ}C$ . From  $T_a = 65$  to  $85^{\circ}C$  a derating factor of  $-10$  mW/ $^{\circ}C$  shall be applied until 300 mW.

## Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2 to 6	V
Input voltage	$V_{IN}$	0 to $V_{CC}$	V
Output voltage	$V_{OUT}$	0 to $V_{CC}$	V
Operating temperature	$T_{opr}$	-40 to 85	°C
Input rise and fall time	$t_r, t_f$	0 to 1000 ( $V_{CC} = 2.0$ V) 0 to 500 ( $V_{CC} = 4.5$ V) 0 to 400 ( $V_{CC} = 6.0$ V)	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device.  
Unused inputs must be tied to either  $V_{CC}$  or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition	$T_a = 25^\circ\text{C}$			$T_a = -40$ to $85^\circ\text{C}$		Unit		
			$V_{CC}$ (V)	Min	Typ.	Max	Min		Max	
High-level input voltage	$V_{IH}$	—	2.0	1.50	—	—	1.50	—	V	
			4.5	3.15	—	—	3.15	—		
			6.0	4.20	—	—	4.20	—		
Low-level input voltage	$V_{IL}$	—	2.0	—	—	0.50	—	0.50	V	
			4.5	—	—	1.35	—	1.35		
			6.0	—	—	1.80	—	1.80		
High-level output voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -20 \mu\text{A}$	2.0	1.9	2.0	—	1.9	—	V
				4.5	4.4	4.5	—	4.4	—	
				6.0	5.9	6.0	—	5.9	—	
		QH'	$I_{OH} = -4$ mA	4.5	4.18	4.31	—	4.13	—	V
				6.0	5.68	5.80	—	5.63	—	
				QA to QH	$I_{OH} = -6$ mA	4.5	4.18	4.31	—	
6.0	5.68	5.80	—			5.63	—			
Low-level output voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 20 \mu\text{A}$	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
				6.0	—	0.0	0.1	—	0.1	
		QH'	$I_{OL} = 4$ mA	4.5	—	0.17	0.26	—	0.33	V
				6.0	—	0.18	0.26	—	0.33	
				QA to QH	$I_{OL} = 6$ mA	4.5	—	0.17	0.26	
6.0	—	0.18	0.26			—	0.33			
3-state output off-state current	$I_{OZ}$	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND	6.0	—	—	$\pm 0.5$	—	$\pm 5.0$	$\mu\text{A}$	
Input leakage current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	$\pm 0.1$	—	$\pm 1.0$	$\mu\text{A}$	
Quiescent supply current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	4.0	—	40.0	$\mu\text{A}$	

### Timing Requirements (input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Ta = 25°C		Ta = -40 to 85°C		Unit
			V <sub>CC</sub> (V)	Typ.	Limit	Limit	
Minimum pulse width (SCK, RCK)	$t_W$ (H) $t_W$ (L)	—	2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum pulse width ( $\overline{\text{SCLR}}$ )	$t_W$ (L)	—	2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum set-up time (SI-SCK)	$t_s$	—	2.0	—	50	65	ns
			4.5	—	10	13	
			6.0	—	9	11	
Minimum set-up time (SCK-RCK)	$t_s$	—	2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum set-up time ( $\overline{\text{SCLR}}$ -RCK)	$t_s$	—	2.0	—	100	125	ns
			4.5	—	20	25	
			6.0	—	17	21	
Minimum hold time	$t_h$	—	2.0	—	0	0	ns
			4.5	—	0	0	
			6.0	—	0	0	
Minimum removal time ( $\overline{\text{SCLR}}$ )	$t_{rem}$	—	2.0	—	50	65	ns
			4.5	—	10	13	
			6.0	—	9	11	
Clock frequency	f	—	2.0	—	6	5	MHz
			4.5	—	30	25	
			6.0	—	35	28	

### AC Characteristics ( $C_L = 15 \text{ pF}$ , $V_{CC} = 5 \text{ V}$ , $T_a = 25^\circ\text{C}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time (QH')	$t_{TLH}$	—	—	4	8	ns
	$t_{THL}$					
Propagation delay time (SCK-QH')	$t_{pLH}$	—	—	12	21	ns
	$t_{pHL}$					
Propagation delay time ( $\overline{\text{SCLR}}$ -QH')	$t_{pHL}$	—	—	15	30	ns
Maximum clock frequency	$f_{max}$	—	35	77	—	MHz

## AC Characteristics (input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition			Ta = 25°C			Ta = -40 to 85°C		Unit
			CL (pF)	V <sub>CC</sub> (V)	Min	Typ.	Max	Min	Max	
Output transition time (Q <sub>n</sub> )	t <sub>TLH</sub> t <sub>THL</sub>	—	50	2.0	—	25	60	—	75	ns
				4.5	—	7	12	—	15	
				6.0	—	6	10	—	13	
Output transition time (QH')	t <sub>TLH</sub> t <sub>THL</sub>	—	50	2.0	—	30	75	—	95	ns
				4.5	—	8	15	—	19	
				6.0	—	7	13	—	16	
Propagation delay time (SCK-QH')	t <sub>pLH</sub> t <sub>pHL</sub>	—	50	2.0	—	45	125	—	155	ns
				4.5	—	15	25	—	31	
				6.0	—	13	21	—	26	
Propagation delay time ( $\overline{\text{SCLR}}$ -QH')	t <sub>pHL</sub>	—	50	2.0	—	60	175	—	220	ns
				4.5	—	18	35	—	44	
				6.0	—	15	30	—	37	
Propagation delay time (RCK-Q <sub>n</sub> )	t <sub>pLH</sub> t <sub>pHL</sub>	—	50	2.0	—	60	150	—	190	ns
				4.5	—	20	30	—	38	
				6.0	—	17	26	—	32	
			150	2.0	—	75	190	—	240	
				4.5	—	25	38	—	48	
				6.0	—	22	32	—	41	
Output enable time	t <sub>pZL</sub> t <sub>pZH</sub>	R <sub>L</sub> = 1 kΩ	50	2.0	—	45	135	—	170	ns
				4.5	—	15	27	—	34	
				6.0	—	13	23	—	29	
			150	2.0	—	60	175	—	220	
				4.5	—	20	35	—	44	
				6.0	—	17	30	—	37	
Output disable time	t <sub>pLZ</sub> t <sub>pHZ</sub>	R <sub>L</sub> = 1 kΩ	50	2.0	—	30	150	—	190	ns
				4.5	—	15	30	—	38	
				6.0	—	14	26	—	33	
Maximum clock frequency	f <sub>max</sub>	—	50	2.0	6	17	—	5	—	MHz
				4.5	30	50	—	25	—	
				6.0	35	59	—	28	—	
Input capacitance	C <sub>IN</sub>	—	—	—	—	5	10	—	10	pF
Power dissipation capacitance	C <sub>PD</sub> (Note)	—	—	—	—	184	—	—	—	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

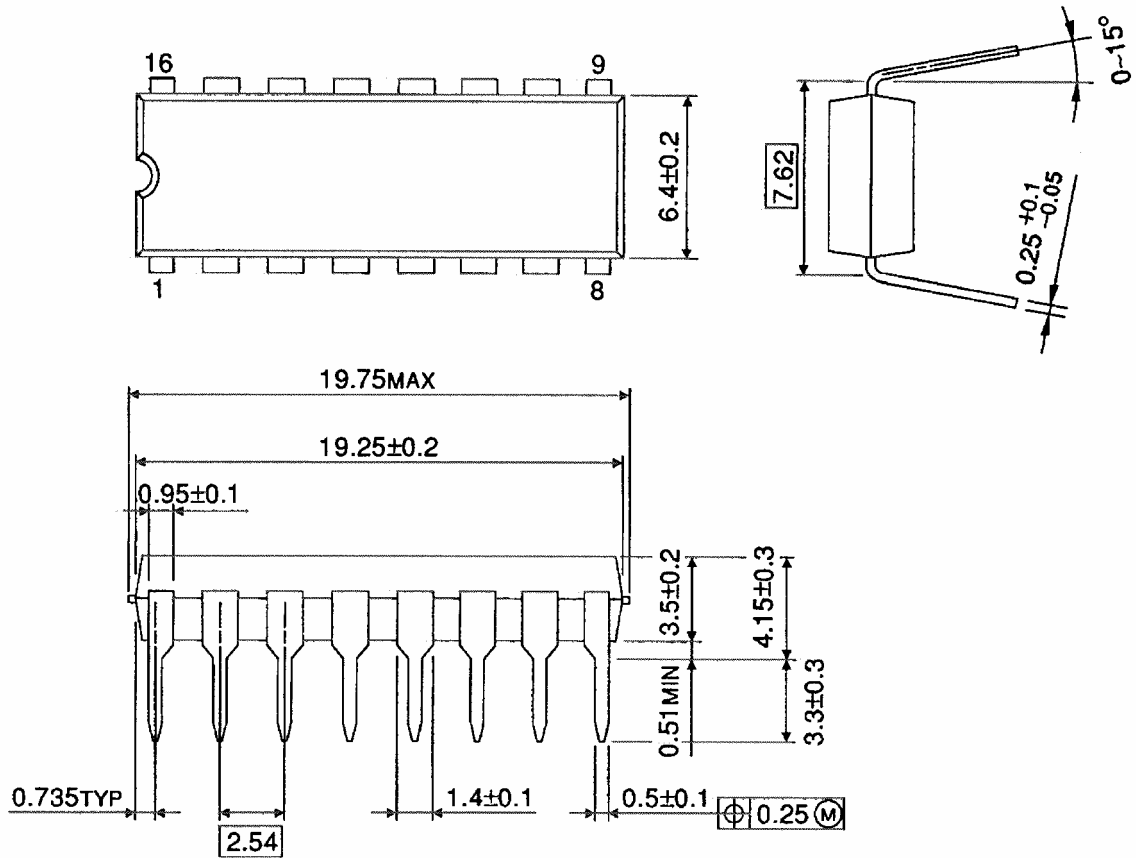
Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## Package Dimensions

DIP16-P-300-2.54A

Unit : mm



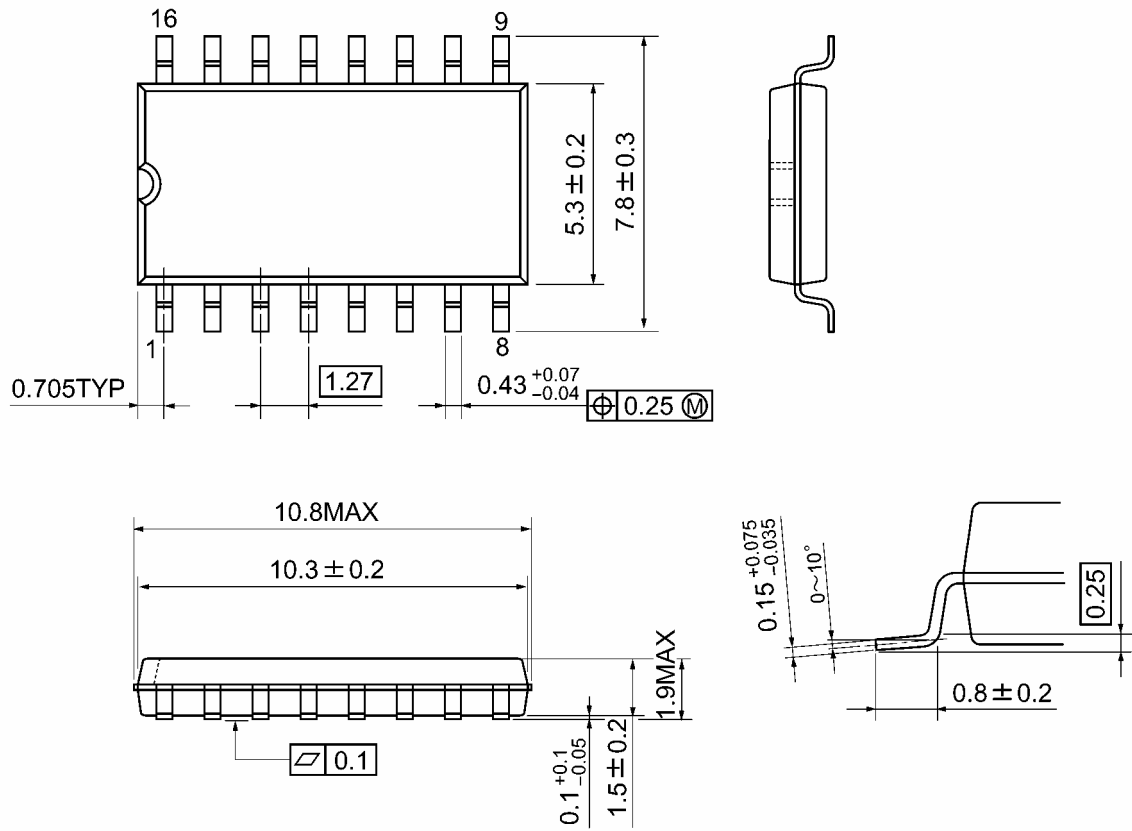
Weight: 1.00 g (typ.)



## Package Dimensions

SOP16-P-300-1.27A

Unit: mm

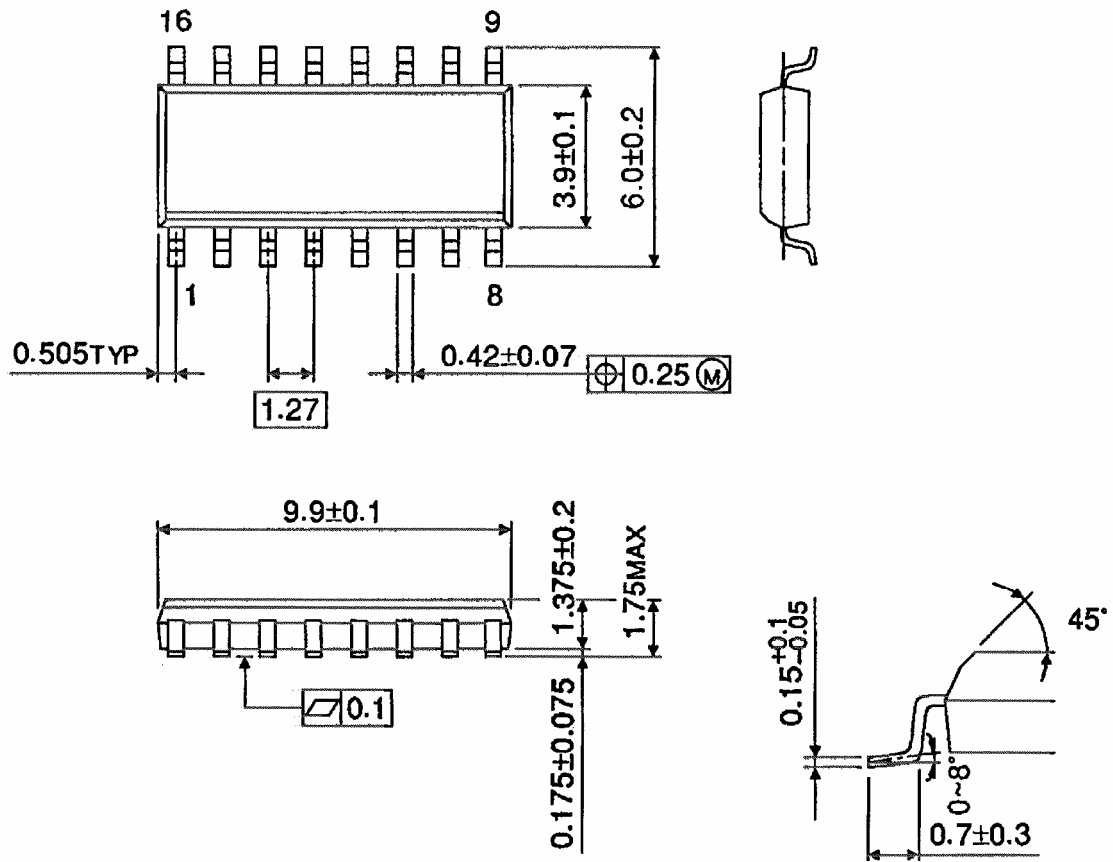


Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL16-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

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20070701-EN GENERAL

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